X3G-OH047; X3T-OH047; X3G-OH048; X3T-OH048

Magnetic field sensor

Rev. 1 — 4 April 2011

Product specification

1. Product profile

1.1 General description

The X3G-OH047, X3G-OH048, X3T-OH047 and X3T-OH048 are sensitive magnetic field sensors, employing the magneto-resistive effect of thin film permalloy. The sensors contain two parallel supplied Wheatstone bridges at a relative angle of 45° to each other.

A rotating magnetic field in the surface parallel to the chip (x-y plane) will deliver two independent sinusoidal output signals, one following a $cos(2\alpha)$ and the other following a $sin(2\alpha)$ function, α being the angle between sensor and field direction (see Figure 5 and Figure 6).

The X3G-OH047, X3G-OH048, X3T-OH047 and X3T-OH048 are suited for high precision angle measurement applications under low field conditions (saturation field strength 25 kA/m).

The sensors can be operated at any frequency between DC and 1 MHz.

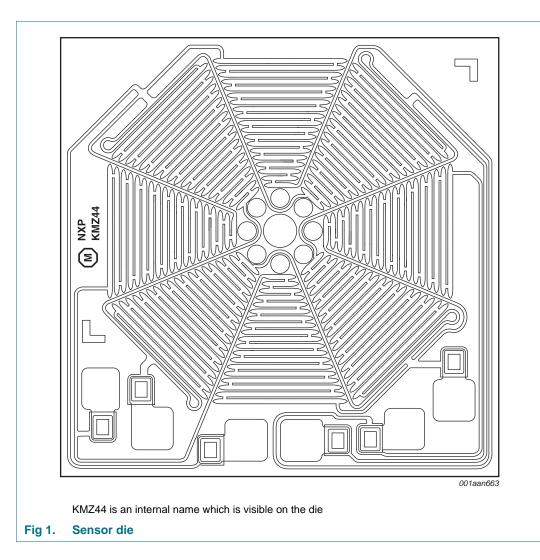
All type numbers shown in this data sheet are valid for a single-die (single sensor). The double-die has two magnetic field sensors with electrical and magnetic parameters which fulfill the specified single-die values and do not correlate to each other.

Table 1. Product overview

Type number	Sensor	Packing
X3G-OH047	double-die	sawn wafer; on foil
X3G-OH048	single-die	sawn wafer; on foil
X3T-OH047	double-die	taped on reel
X3T-OH048	single-die	taped on reel



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1.2 Features and benefits

- Accurate and reliable angle measurement
- Mechanical robustness, contactless principle
- Wear-free operation
- Accuracy independent of mechanical tolerances
- Extended temperature range

1.3 Applications

- Steering angle and torsion
- Headlight adjustment
- Motor positioning

- Window wipers
- Fuel level
- Mirror positioning

1.4 Quick reference data

Table 2. Quick reference data

 $T_{amb} = 25 \text{ °C}; H_{ext} = 25 \text{ kA/m}; V_{CC} = 5 \text{ V}; unless otherwise specified.}$

anno	0,11		•				
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{CC}	supply voltage			-	5	9	V
V _M	peak voltage	see Figure 3	[1][2]	60	67	75	mV
V _{offset}	offset voltage	per supply voltage; see <u>Figure 3</u>	<u>[1]</u>	-2	-	+2	mV/V
TC _{V(offset)}	offset voltage temperature coefficient	per supply voltage; $T_{amb} = -40 \text{ °C to } +150 \text{ °C};$ see Figure 3	<u>[1][3]</u>	-2	-	+2	(μV/V)/K
R _{bridge}	bridge resistance		<u>[1][4]</u>	2.7	3.2	3.7	kΩ

[1] Applicable for bridge 1 and bridge 2.

[2] $V_M = |V_{O(max)} - V_{offset}|$. Periodicity of V_M : sin(2 α) and cos(2 α), respectively.

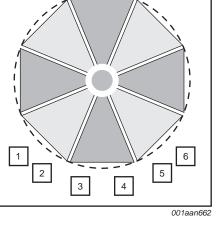
$$[3] \quad TC_{V(offset)} = \frac{V_{offset}(at \ 150 \ ^{\circ}C) - V_{offset}(at \ -40 \ ^{\circ}C)}{150 \ ^{\circ}C - (-40 \ ^{\circ}C)}$$

[4] Bridge resistance between pad 5 to pad 1 and pad 4 to pad 2.

Pinning information 2.

Table 3. Pinning

		5	
Pad	Symbol	Description	Simplified outline
1	ON1	output voltage bridge 1	
2	ON2	output voltage bridge 2	
3	GND	common ground	
4	OP2	output voltage bridge 2	
5	OP1	output voltage bridge 1	
6	V _{CC}	common bridge supply voltage	

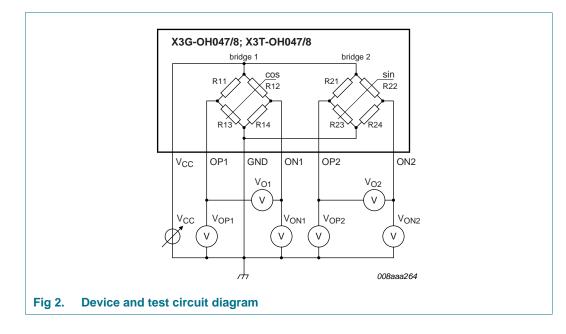


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3. Ordering information

Table 4. Ordering information							
Type number	Package	Package					
	Name	Description	Version				
X3G-OH047	bare die	double-die; sawn wafer; on foil	OL-X3G-OH047				
X3G-OH048	bare die	single-die; sawn wafer; on foil	OL-X3G-OH048				
X3T-OH047	bare die	double-die; taped on reel	OL-X3T-OH047				
X3T-OH048	bare die	single-die; taped on reel	OL-X3T-OH048				

4. Circuit diagram



5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		•••	,		
Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-	9	V
H _{ext}	external magnetic field strength		<u>[1]</u> 25	-	kA/m
T _{amb}	ambient temperature		-40	+150	°C

[1] Minimum stimulating magnetic field parallel to the chip surface (x-y plane) to achieve specified angular accuracy.

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6. Characteristics

Table 6. Characteristics

 $T_{amb} = 25 \text{ °C}; H_{ext} = 25 \text{ kA/m}^{[1]}; V_{CC} = 5 \text{ V}; unless otherwise specified.}$

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{CC}	supply voltage			-	5	9	V
V _M	peak voltage	see Figure 3	[2][3]	60	67	75	mV
TC _{VM}	peak voltage temperature coefficient	$T_{amb} = -40 \ ^{\circ}C$ to +150 $^{\circ}C$	<u>[2][4]</u>	-0.30	-0.36	-0.42	%/K
R _{bridge}	bridge resistance		[2][5]	2.7	3.2	3.7	kΩ
TC _{R(bridge)}	bridge resistance temperature coefficient	$T_{amb} = -40 \text{ °C to } +150 \text{ °C}$	[2][6]	0.24	0.27	0.29	%/K
V _{offset}	offset voltage	per supply voltage; see <u>Figure 3</u>	<u>[2]</u>	-2	-	+2	mV/V
TC _{V(offset)}	offset voltage temperature coefficient	per supply voltage; T _{amb} = -40 °C to +150 °C; see <u>Figure 3</u>	[2][7]	-2	-	+2	(μV/V)/K
V _{o(hys)}	hysteresis output voltage	see Figure 4	[2][8]	0	0.05	0.18	%FS
ω	angular velocity			0	-	1	MHz
k	amplitude synchronism		<u>[9]</u>	98.9	100	101.1	%
TC _k	amplitude synchronism temperature coefficient	T_{amb} = -40 °C to +150 °C	<u>[10]</u>	-0.01	0	+0.01	%/K
Δα	angular inaccuracy		[11]	0	0.05	0.1	deg

[1] Minimum stimulating magnetic field parallel to the chip surface (x-y plane) to achieve angular inaccuracy.

[2] Applicable for bridge 1 and bridge 2.

 $[3] \quad V_{M} = |V_{O(max)} - V_{offset}|. \mbox{ Periodicity of } V_{M}: sin(2\alpha) \mbox{ and } cos(2\alpha), \mbox{ respectively}.$

[4]
$$TC_{VM} = \frac{V_M(at\ 150\ ^\circ C) - V_M(at\ -40\ ^\circ C)}{V_M(at\ 25\ ^\circ C) \times (150\ ^\circ C - (-40\ ^\circ C))}$$

[5] Bridge resistance between pad 5 to pad 1 and pad 4 to pad 2.

$$[6] \quad TC_{R(bridge)} = \frac{R_{bridge}(at\ 150\ ^{\circ}C) - R_{bridge}(at\ -40\ ^{\circ}C)}{R_{bridge}(at\ 25\ ^{\circ}C) \times (150\ ^{\circ}C - (-40\ ^{\circ}C))}$$

[7]
$$TC_{V(offset)} = \frac{V_{offset}(at \ 150 \ ^{\circ}C) - V_{offset}(at \ -40 \ ^{\circ}C)}{150 \ ^{\circ}C - (-40 \ ^{\circ}C)}$$

$$[8] \quad V_{o(hys)I} = \left| \frac{V_{OI}(67.5^{\circ})135^{\circ} \to 45^{\circ} - V_{OI}(67.5^{\circ})45^{\circ} \to 135^{\circ}}{2 \times V_{MI}} \right|$$
$$V_{o(hys)2} = \left| \frac{V_{O2}(22.5^{\circ})90^{\circ} \to 0^{\circ} - V_{O2}(22.5^{\circ})0^{\circ} \to 90^{\circ}}{2 \times V_{M2}} \right|$$

$$[9] \quad k = \frac{V_{M1}}{V_{M2}}$$

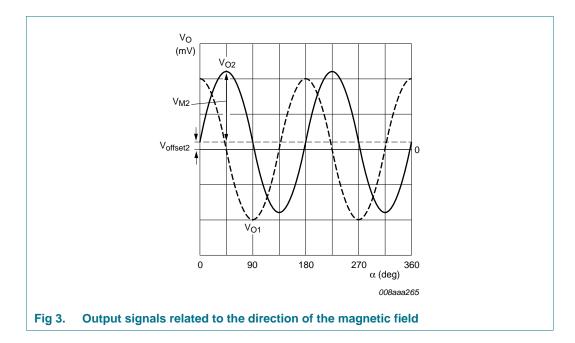
[10]
$$TC_k = \frac{k(at \ 150 \ ^\circ C) - k(at \ -40 \ ^\circ C)}{k(at \ 25 \ ^\circ C) \times (150 \ ^\circ C - (-40 \ ^\circ C))}$$

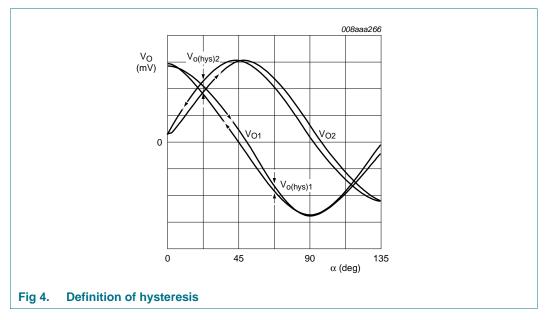
[11] $\Delta \alpha = |\alpha_{real} - \alpha_{meas}|$; V_{offset} = 0 V; inaccuracy of angular measurement due to deviations from ideal sinusoidal characteristics, calculated from the third and fifth harmonics of the spectrum V_O.

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7. Bare die outline

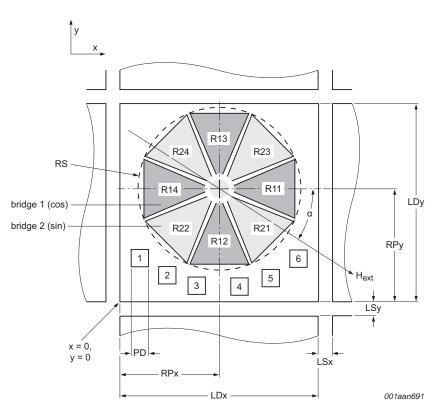


Fig 5. Bare die outline (single die)

Table 7.	Mechanical dimensions for Figure 5					
Symbol	Parameter	x	У	Radius/diameter	Unit	
LD	die size	1150	1150	-	μ m	
LS	sawing lane width	60	60	-	μ m	
RP	reading point position	575	642	-	μ m	
RS	sensitive area radius	-	-	480	μ m	
PD	pad diameter	-	-	110	μ m	
1	position pad 1	108	230	-	μ m	
2	position pad 2	243	125	-	μ m	
3	position pad 3	489	95	-	μ m	
4	position pad 4	632	95	-	μ m	
5	position pad 5	900	125	-	μ m	
6	position pad 6	1032	200	-	μm	

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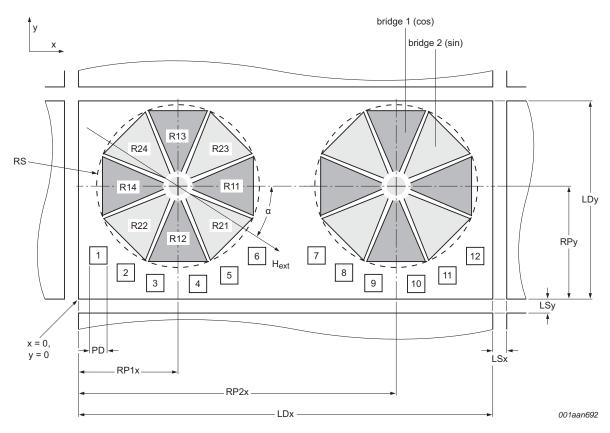


Fig 6. Bare die outline (double die)

Table 8. Mechanical dimensions for Figure 6

Symbol	Parameter	x	У	Radius/diameter	Unit
LD	die size	2360	1150		μm
LS	sawing lane width	60	60		μm
RP1	reading point position 1	575	642		μm
RP2	reading point position 2	1785	642		μm
RS	sensitive area radius	-	-	480	μm
PD	pad diameter	-	-	110	μm
1	position pad 1	108	230		μm
2	position pad 2	243	125		μm
3	position pad 3	489	95		μm
4	position pad 4	632	95		μm
5	position pad 5	900	125		μm
6	position pad 6	1032	200		μm
7	position pad 7	1318	230		μm
8	position pad 8	1453	125		μm
9	position pad 9	1699	95		μm

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150

 $\textbf{380} \pm \textbf{15}$

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mm

μm

Symbol	Parameter		1	/alue	Unit
Table 9.	Wafer dimensions				
12	position pad 12	2242	200		μm
11	position pad 11	2110	125		μm
10	position pad 10	1842	95		μm
Symbol	Parameter	x	У	Radius/diameter	Unit
Table 8.	Mechanical dimensions for Figure	6 continued			

8. Packing information

wafer diameter

wafer thickness

WD

WT

8.1 Tape construction for X3G-OH047 and X3G-OH048

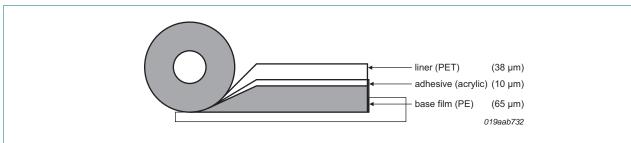


Fig 7. Tape construction

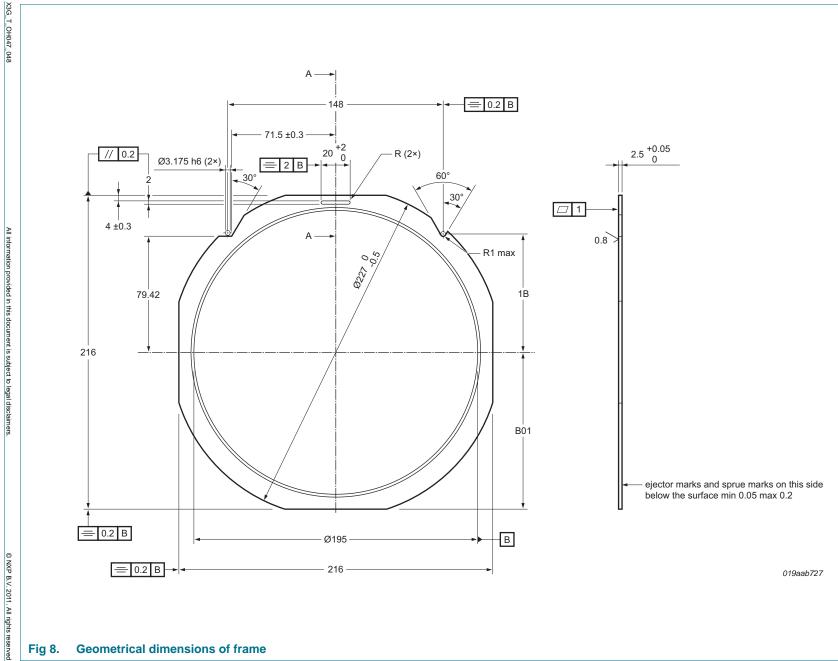
Table 10. Material composition

Content	Typical value	Unit
-	75	μm
-	55 / 20	g/mm
Na+	0.027	μg/ml
K+	< 0.004	μg/ml
CI	0.045	μg/ml
	- - Na ⁺ K ⁺	- 75 - 55 / 20 Na ⁺ 0.027 K ⁺ < 0.004

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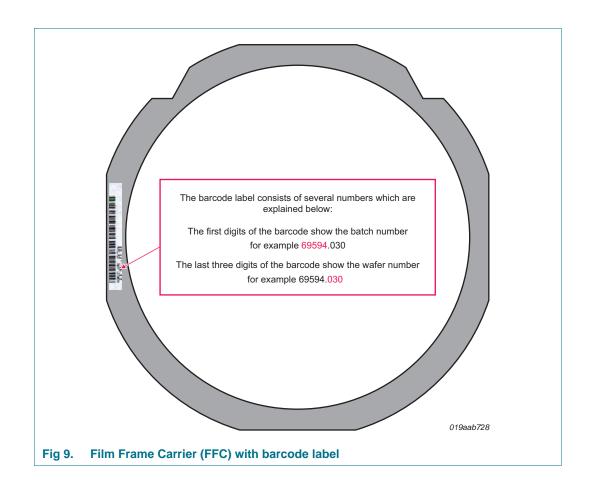


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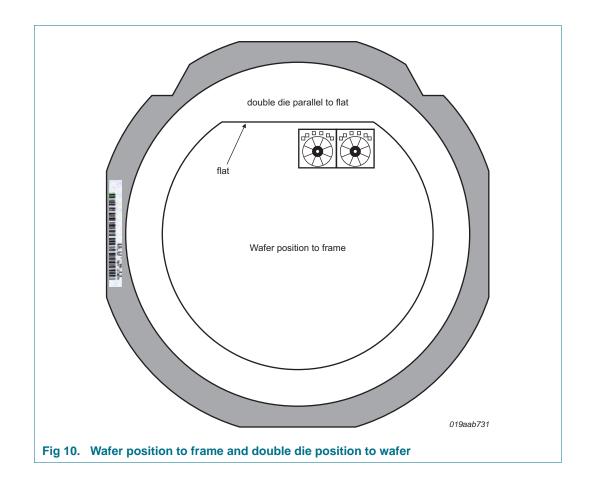


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8.2 Carrier tape for X3T-OH047 and X3T-OH048

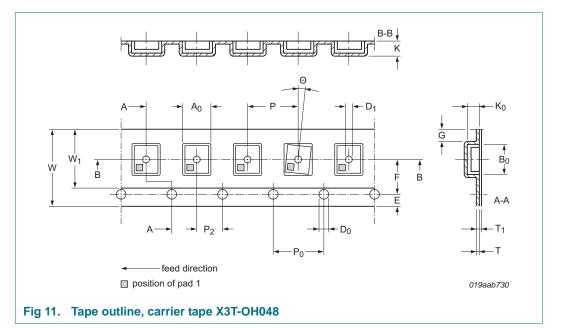


Table 11. Dimensions for Figure 11 "Tape outline, carrier tape X3T-OH048"

Item	Symbol	Specification			
		Dimension [mm]	Tolerance		
Overall dimensions					
Tape width	W	8	±0.1		
Thickness	К	≤ 1.2	-		
Distance	G	≥ 0.75	-		
Sprocket holes					
Diameter	D ₀	1.5	±0.1		
Distance	E	1.75	±0.1		
Pitch ^[1]	P ₀	4	±0.1		
Distance between cente	er lines				
Length direction	P ₂	2	±0.05		
Width direction	F	3.5	±0.05		
Compartments					
Length	A ₀	1.4	±0.05		
Width	B ₀	1.4	±0.05		
Depth	K ₀	0.8	±0.05		
Hole diameter	D ₁	0.5	±0.1		
Pitch	Р	4	±0.1		
Device					
Outline	X3T-OH048	}			
Rotation	Θ	$\leq 20^{\circ}$	-		
Carrier tape antistatic					
Film thickness ^[2]	Т	0.25	±0.07		
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 Table 11. Dimensions for Figure 11 "Tape outline, carrier tape X3T-OH048" ... continued

Item	Symbol	Specification		
		Dimension [mm]	Tolerance	
Cover tape				
Width	W ₁	≤ 5.75	-	
Film thickness	T ₁	≤ 0.1	-	
Bending radius				
In winding direction	R	≥ 30	-	

[1] Cumulate pitch error ± 0.2 over 10 pitch.

[2] Carbon loaded polystyrene 100 % recyclable.

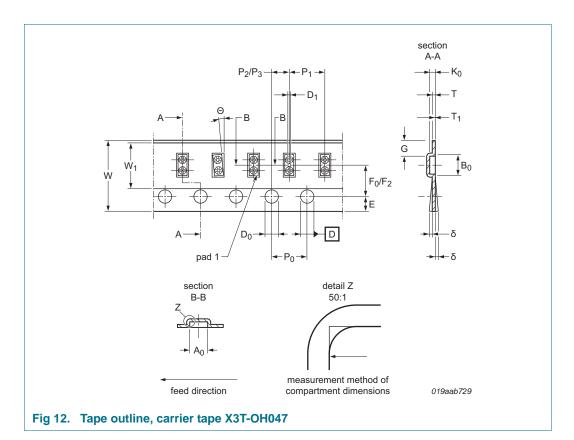


Table 12	Dimensions for	Figure 12	2 "Tane outline	carrier tane	X3T-OH047"
		FIGULE I	L Tabe outline.	carrier labe	A31-01047

Item	Symbol	Specification		
		Dimension [mm]	Tolerance	
Overall dimensions				
Tape width	W	8	±0.1	
Distance	G	≥ 0.75	-	
Sprocket holes				
Diameter	D ₀	1.5	±0.1	
Distance	E	1.75	±0.1	
Pitch ^[1]	P ₀	4	±0.1	

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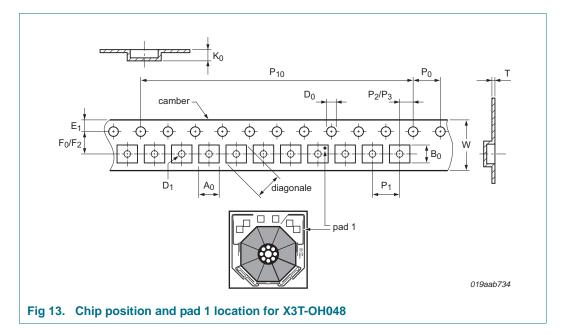
Item	Symbol	Specification	Specification		
		Dimension [mm]	Tolerance		
Distance between center line	s		ľ		
Sprocket hole / cavity center	P ₂	2	±0.05		
Sprocket hole / cavity hole	P ₃	2	±0.05		
Sprocket hole / cavity center	F ₀	3.5	±0.05		
Sprocket hole / cavity hole	F_2	3.5	±0.05		
Compartments					
Length	A ₀	1.4	±0.05		
Width overall	B ₀	2.7	±0.05		
Depth	K ₀	0.5	±0.05		
Hole diameter	D ₁	0.5	±0.1		
Pitch	P ₁	4	±0.1		
Device					
Outline	X3T-OH047				
Rotation	Θ	≤ 15 °	-		
Carrier tape antistatic					
Film thickness ^[2]	Т	0.25	±0.07		
Bend	δ	≤ 0.3	-		
Cover tape					
Width	W ₁	5.3	±0.1		
Film thickness	T ₁	0.05	±0.01		
Bending radius					
In winding direction	R	≥ 30	-		

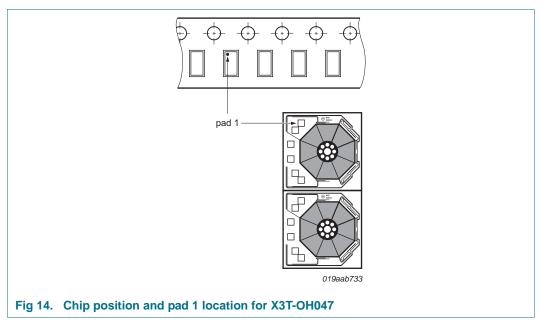
ensions for Figure 12 "Tape outline, carrier tape X3T-OH047" continued Dim

[1] Cumulate pitch error ± 0.2 over 10 pitch.

[2] Carbon loaded polystyrene 100 % recyclable.

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9. Revision history

Table 13. Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
X3G_T_OH047_048 v.1	20110404	Product specification	-	-

X3G_T_OH047_048

10. Legal information

10.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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X3G_T_OH047_048

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